

Notice of References Cited	Application/Control No. 09/870,811	Applicant(s)/Patent Under Reexamination SMITH ET AL.	
	Examiner Djenane M Bayard	Art Unit 2141	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0115122	06-2003	Slater et al.	705/35
	B	US-2002/0112056	08-2002	Baldwin et al.	709/225
	C	US-6,799,196	09-2004	Smith, Kim C.	709/203
	D	US-2002/0013853	01-2002	Baber et al.	709/232
	E	US-2002/0138389	09-2002	Martone et al.	705/36
	F	US-6,513,019	01-2003	Lewis, Charles J.	705/35
	G	US-6,571,274	05-2003	Jacobs et al.	709/203
	H	US-6,708,213	03-2004	Bommaiah et al.	709/226
	I	US-6,480,940	11-2002	Aino, Shigeyuki	711/141
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.